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## 银纳米晶体薄膜在纳米压痕下的微结构转变

臧鹏,张跃飞\*,刘攀,韩晓东,张泽

摘要 参考文献 相关文章

2011年 第30卷 第6期: 1000-6281(2011)06-0483-05 下载地址: 点

摘要:利用直流磁控溅射在SiO<sub>2</sub>/Si双层基底上制备厚度为60 nm的银纳米晶体薄膜,使用纳米压痕仪对其进行压痕,使用原子力显微镜对压痕区域进行形貌 表征,将压痕后的银薄膜转移到透射电子显微镜中观察研究微结构变化。结果表明,压痕区域呈正三角形,边缘有堆起现象;压痕前沉积态薄膜的晶粒较小 呈等轴状,压痕后晶粒较大一般呈条带状,长度方向垂直于压痕边缘;压痕区域内的晶粒内出现了大量的形变孪晶,孪晶方向一般亦垂直于压痕边缘。 关键词:银;纳米压痕;透射电子显微镜;形变孪晶

中图分类号: O614.122; TH140; TG115.21+5.3; O762

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Abstract: Silver nanocrystalline film with a thickness of 60 nm was deposited on SiO<sub>2</sub>/Si substrate by DC magnetron sputtering. Nanoindentation tests were performed on silver film. Atomic Force Microscope was utilized to characterize morphology of the indentation area. The film with the indented area was transferred into Transmission Electron Microscope for further investigation. The results showed that the indented area had a shape of triangle and pile-up was observed along the indentation edge; after the indentation, smaller equi-axial grains of the silver thin film became larger columnar grains, whose length direction was perpendicular to the triangle edge; plenty of deformation twinning were introduced into the indentation area with their direction also perpendicular to the indentation edge.

Keywords: silver; nanoindentation; TEM; deformation twinning

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